



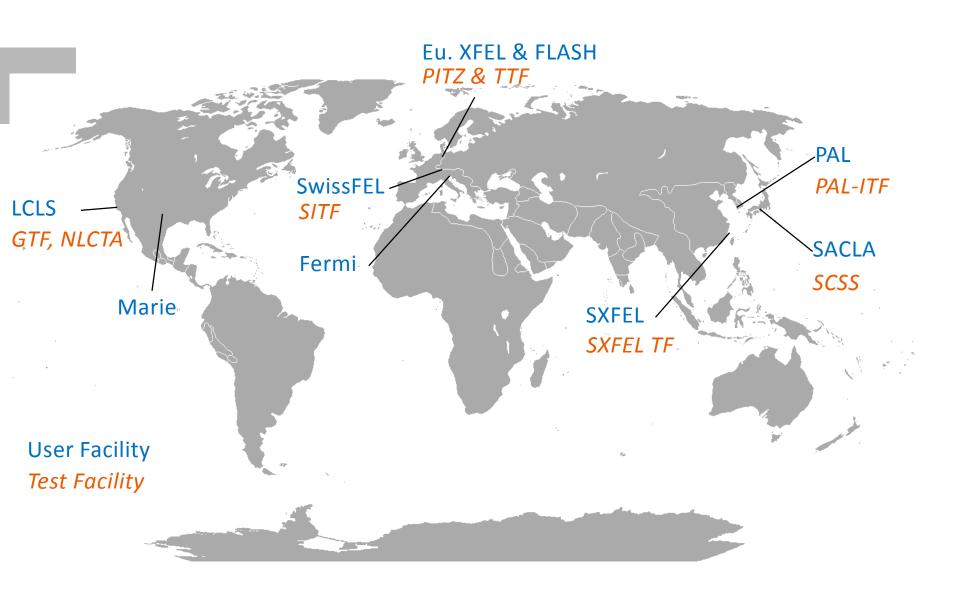
**Sven Reiche:: SwissFEL Beam Dynamics :: Paul Scherrer Institut** 

# Studies at the SwissFEL Injector Test Facility

Insert the occasioCALIFES Workshop, Oct 2016

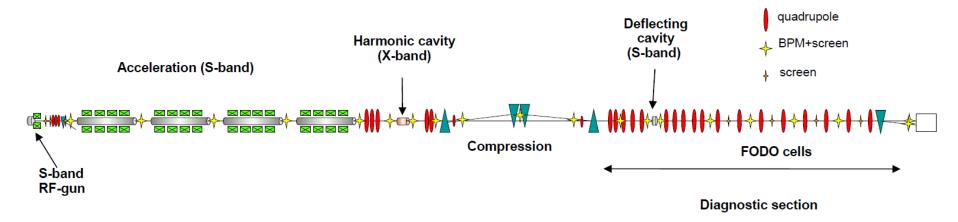


### X-ray FEL Facilities and Their Test Facilities





## SwissFEL Injector Test Facility



- Goals
  - Demonstrate beam quality needed for SwissFEL
  - Demonstrate preserved beam qualities after compression
  - Demonstrate performance of new diagnostics
  - Test in-vacuum undulator U15 and demonstrate FEL amplification
- Operation 2010-2014



### Summary of beam physics studies at SITF

### **Beam and lattice characterization procedures**

- Transverse beam characterization
  - Symmetric single-quad scan [E. Prat, NIMA 743, 103 (2014)]
  - 4D measurements [E. Prat and M. Aiba, PRSTAB 17, 052801 (2014)]
  - Beam-size free optics measurements [M. Aiba et al, NIMA 753, 24 (2014)]
  - SwissFEL profile monitor [R. Ischebeck et al, PRSTAB 18, 082802 (2015)]
- Longitudinal beam characterization and time-resolved measurements
  - Measurement of bunch length (TD) and beam slice parameters with transverse deflector and dispersion method [E. Prat and M. Aiba, PRSTAB 17, 032801 (2014)]

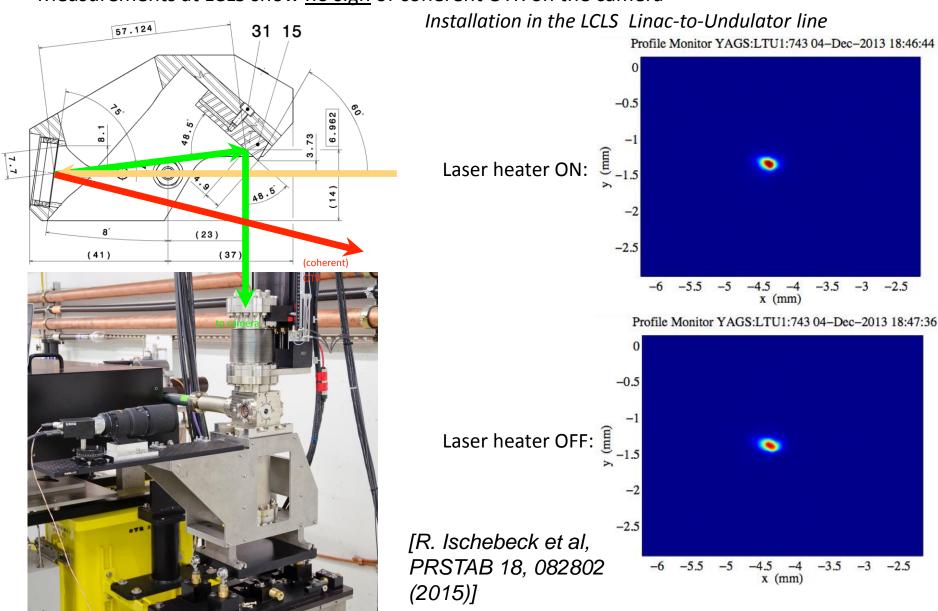
#### **Beam physics results**

- Cathode (thermal/intrinsic) emittance measurements:
  - Wavelength dependence [M. C. Divall et al, PRSTAB 18, 033401 (2015)]
  - Gradient dependence [E. Prat et al, PRSTAB 18, 063401 (2015)]
  - Copper vs cesium telluride [E. Prat et al, PRSTAB, 043401 (2015)]
- Optimization of uncompressed beam:
  - Measurements [E. Prat et al, PRSTAB 17, 104401 (2014)]
  - Automatic optimization [S. Bettoni et al, PRSTAB 18, 123404 (2015)]
- Emittance preservation at compression [S. Bettoni et al, PRAB 19, 034402 (2016)]
- Further measurements:
  - Passive "streaker" [S. Bettoni et al, PRAB 19, 021304 (2016)]
  - Beam tilts meas. and correction [M. Guetg et al, PRSTAB 18, 030701 (2015)]
  - Comparison FODO vs quad-scan measurements [M. Yan et al, FEL14, 941 (2015)]



### Measurements at LCLS (December 2013)

Measurements at LCLS show <u>no sign</u> of coherent OTR on the camera



### Emittance resolution, errors and matching

- ☐ SwissFEL profile monitor (YAG)
  - Beam size resolution is ~15 μm, equivalent to an emittance resolution of 1-3 nm (E=250MeV)
  - ☐ Signal to noise ratio is good enough to measure slice emittance for bunch charges of less than 1pC

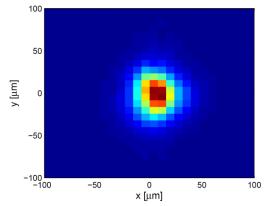
#### **Errors**

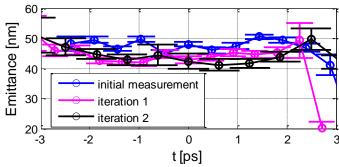
- Statistical errors from beam size variations (what is shown in the error bars of the measurements). For 5% of beam size measurement error this is below 3% (if  $\Delta\mu_x$ =10deg).
- Systematic errors expected to be below 5%:
  - Screen calibration (~1%→~2%) and resolution
  - > Energy and quadrupole field errors (<1%)
  - Optics mismatch
  - Others (e.g. errors associated to Gauss fit)

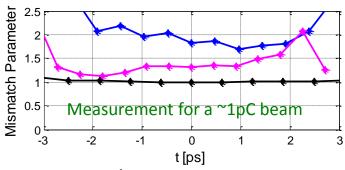
#### Matching

- Beam core is always matched to exclude errors due to optics mismatch
- Matching of the core works normally in 1-2 iterations
- Successful matching gives us confidence in the obtained emittance values

Beam image close to screen resolution limit







$$M = \frac{1}{2} (\beta \gamma_D - 2\alpha \alpha_D + \gamma \beta_D)$$



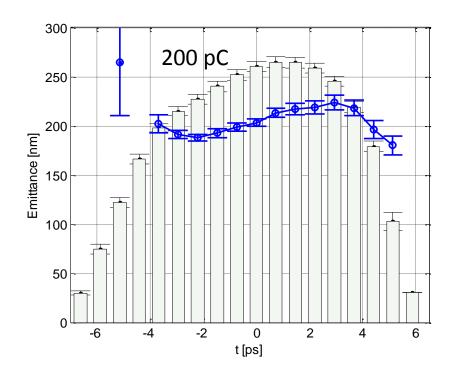
### Optimum emittances

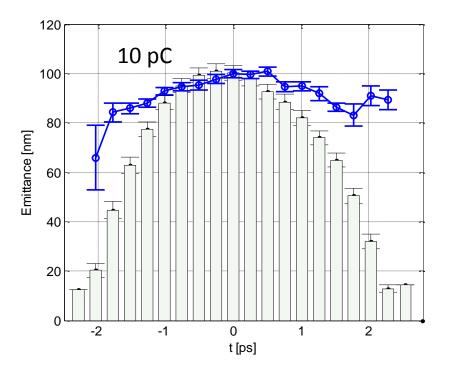
We have achieved the following emittances

[E. Prat et al, PRSTAB 17, 104401 (2014)]

|                     | 200 pC   | 10 pC    |
|---------------------|----------|----------|
| Projected emittance | ~0.30 μm | ~0.15 μm |
| Slice emittance     | ~0.20 μm | ~0.10 μm |

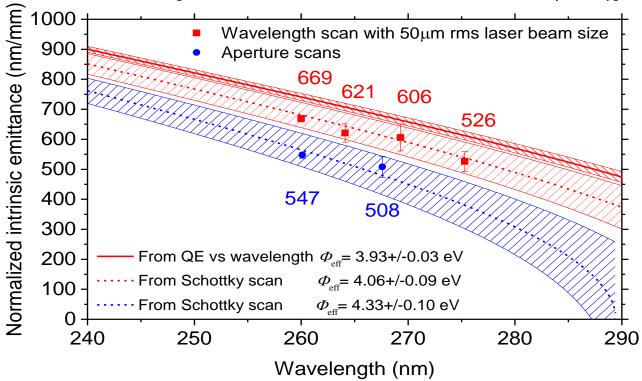
- These emittance values fulfill the SwissFEL requirements
- Emittance values are stable in short-term and optimum settings are reproducible
- Emittance is preserved for compressed bunches after careful adjustment of the optics





# Wavelength dependence: summary

[M. C. Divall et al, PRSTAB 18, 033401 (2015)]



- ➤ Measurements agree well with expected work functions
- $\succ$  Wavelength dependence as expected by theory  $|\mathcal{E}_{th}|/|\sigma_l| \propto \sqrt{\phi_l}$
- Wavelength-scans and Schottky-scans can be used to reconstruct the normalized thermal emittances
- > Same cathode show different work function after one month of operation



### Summary of thermal emittance measurements

| Material              | Meas. day  | $ε_{th}/\sigma_l$ (μm/mm) | Laser wave.<br>(nm) | Cathode field<br>(MV/m) | $arepsilon_{th}/\sigma_{l}$ (norm. *) <b>(µm/mm)</b> |
|-----------------------|------------|---------------------------|---------------------|-------------------------|--|
| Cu-3                  | 31-10-2012 | 0.55±0.01                 | 260.1               | 49.9                    | 0.53±0.01  |
| Cu-3                  | 30-10-2012 | 0.51±0.04                 | 267.6               | 49.9                    | 0.57±0.04  |
| Cu-19                 | 25-09-2013 | $0.44 \pm 0.02$           | 262.0               | 49.9                    | $0.44 \pm 0.02$                                      |
| Cu-19                 | 25-09-2013 | 0.37±0.03                 | 262.0               | 34.8                    | $0.40 \pm 0.03$                                      |
| Cu-19                 | 27-09-2013 | $0.35 \pm 0.03$           | 262.0               | 16.4                    | $0.43 \pm 0.03$                                      |
| Cu-19                 | 04-04-2014 | $0.40 \pm 0.03$           | 262.0               | 49.9                    | $0.40 \pm 0.03$                                      |
| Cu-22                 | 13-04-2014 | $0.58 \pm 0.03$           | 262.0               | 76                      | $0.54 \pm 0.03$                                      |
| Cs <sub>2</sub> Te-8  | 04-04-2014 | 0.54±0.06                 | 262.0               | 49.9                    | 0.54±0.06  |
| Cs <sub>2</sub> Te-17 | 08-04-2014 | $0.54 \pm 0.01$           | 266.6               | 76.0                    | 0.54±0.01  |
| Cs <sub>2</sub> Te-17 | 08-04-2014 | 0.50±0.02                 | 266.6               | 76.0                    | 0.51±0.02  |
| Cs <sub>2</sub> Te-17 | 08-04-2014 | 0.52±0.02                 | 266.6               | 76.0                    | 0.53±0.02  |

Wavelength dependence
Cathode field dependence
Cs<sub>2</sub>Te measurements

Measurements at other labs

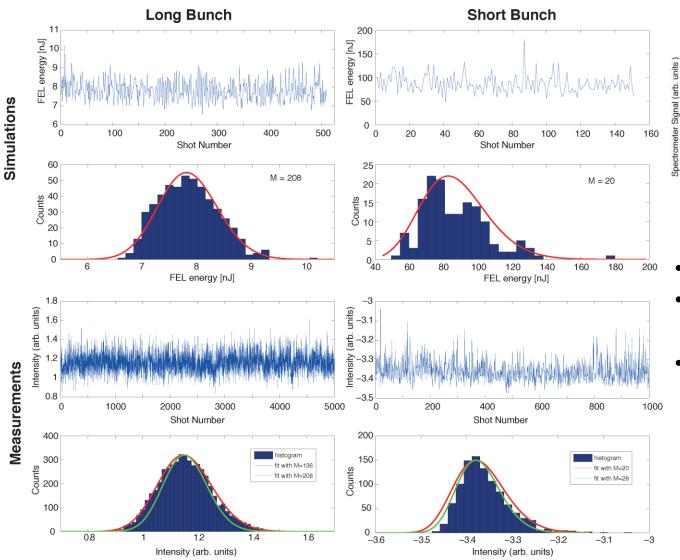
Cu: ~0.9 μm/mm [H. J. Qian et al, PRSTAB 15, 040102 (2012)], [Y. Ding et al, PRL. 102, 254801 (2009)]

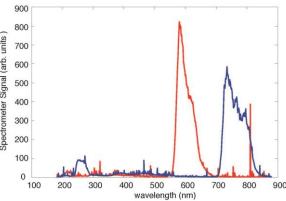
 $Cs_2Te: > 1 \mu m/mm$  [F. Stephan et al., PRSTAB 13, 020704 (2010)]

(\*) Normalized to 262 nm and 50 MV/m



### First FEL in Switzerland





- Test of U15 undulator
- Very little diagnostics (YAG screen, spectrometer)
- Good agreement with numerical model though no further insight into beam parameters.



### Lessons learnt from SITF

- "The injector is moved as it is to SwissFEL" has become obsolete:
  - Emittance optimization requires a longer drift between gun and first RF structures
  - Laser heater was not implemented yet
  - Active correction with quads, skew quads and sextupoles in chicane added
  - Dedicated FODO lattice for diagnostics is impractical (required length, resolution problems on screen, multiple screens, space charge effects increased)
  - Increase of nominal beam energy of first compression stage and longer bunch compressor
  - Cu-cathode and pulse stacking is major cause of microbunching.
  - Tunability in gun laser wavelength for smaller thermal emittances is not worth the effort with respect to increased operation cost and stability.
  - Design of large good field region for chicane magnets causes huge stray field
  - In efficient matching before compressor (high k₁ values and beam chirp)



### Things, which could have been studied...

- New Gun Design (C-Band gun)
- Laser Seeding at 50 nm (HHG vs HGHG vs EEHG)
- Non-linear compression
- Advanced phase-space manipulation with wakes
- Measurement of intrinsic energy spread, Coulomb scattering in the gun.
- More longitudinal diagnostics (invasive and non-invasive)
- Beam based THz generation (moved to FLUTE/KIT)
- Microbunch gain curve

Some will be measured at SwissFEL, though in the future it is foreseen to rebuilt SITF in a reduced form, mostly for Gun and RF testing.



# Acknowledgement

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